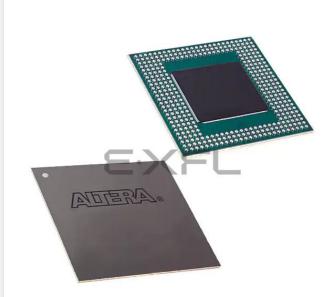
E·XF

Intel - EP20K60EBC356-1X Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Det	ta	i.	ls

Details	
Product Status	Obsolete
Number of LABs/CLBs	2560
Number of Logic Elements/Cells	2560
Total RAM Bits	32768
Number of I/O	196
Number of Gates	162000
Voltage - Supply	1.71V ~ 1.89V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	356-LBGA
Supplier Device Package	356-BGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep20k60ebc356-1x

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

All APEX 20K devices are reconfigurable and are 100% tested prior to shipment. As a result, test vectors do not have to be generated for fault coverage purposes. Instead, the designer can focus on simulation and design verification. In addition, the designer does not need to manage inventories of different application-specific integrated circuit (ASIC) designs; APEX 20K devices can be configured on the board for the specific functionality required.

APEX 20K devices are configured at system power-up with data stored in an Altera serial configuration device or provided by a system controller. Altera offers in-system programmability (ISP)-capable EPC1, EPC2, and EPC16 configuration devices, which configure APEX 20K devices via a serial data stream. Moreover, APEX 20K devices contain an optimized interface that permits microprocessors to configure APEX 20K devices serially or in parallel, and synchronously or asynchronously. The interface also enables microprocessors to treat APEX 20K devices as memory and configure the device by writing to a virtual memory location, making reconfiguration easy.

After an APEX 20K device has been configured, it can be reconfigured in-circuit by resetting the device and loading new data. Real-time changes can be made during system operation, enabling innovative reconfigurable computing applications.

APEX 20K devices are supported by the Altera Quartus II development system, a single, integrated package that offers HDL and schematic design entry, compilation and logic synthesis, full simulation and worst-case timing analysis, SignalTap logic analysis, and device configuration. The Quartus II software runs on Windows-based PCs, Sun SPARCstations, and HP 9000 Series 700/800 workstations.

The Quartus II software provides NativeLink interfaces to other industrystandard PC- and UNIX workstation-based EDA tools. For example, designers can invoke the Quartus II software from within third-party design tools. Further, the Quartus II software contains built-in optimized synthesis libraries; synthesis tools can use these libraries to optimize designs for APEX 20K devices. For example, the Synopsys Design Compiler library, supplied with the Quartus II development system, includes DesignWare functions optimized for the APEX 20K architecture. Figure 11 shows the intersection of a row and column interconnect, and how these forms of interconnects and LEs drive each other.



Figure 11. Driving the FastTrack Interconnect

APEX 20KE devices include an enhanced interconnect structure for faster routing of input signals with high fan-out. Column I/O pins can drive the FastRow[™] interconnect, which routes signals directly into the local interconnect without having to drive through the MegaLAB interconnect. FastRow lines traverse two MegaLAB structures. Also, these pins can drive the local interconnect directly for fast setup times. On EP20K300E and larger devices, the FastRow interconnect drives the two MegaLABs in the top left corner, the two MegaLABs in the top right corner, the two MegaLABS in the bottom left corner, and the two MegaLABs in the bottom right corner. On EP20K200E and smaller devices, FastRow interconnect drives the two MegaLABs on the top and the two MegaLABs on the bottom of the device. On all devices, the FastRow interconnect drives all local interconnect in the appropriate MegaLABs except the local interconnect on the side of the MegaLAB opposite the ESB. Pins using the FastRow interconnect achieve a faster set-up time, as the signal does not need to use a MegaLAB interconnect line to reach the destination LE. Figure 12 shows the FastRow interconnect.

ESBs can implement synchronous RAM, which is easier to use than asynchronous RAM. A circuit using asynchronous RAM must generate the RAM write enable (WE) signal, while ensuring that its data and address signals meet setup and hold time specifications relative to the WE signal. In contrast, the ESB's synchronous RAM generates its own WE signal and is self-timed with respect to the global clock. Circuits using the ESB's selftimed RAM must only meet the setup and hold time specifications of the global clock.

ESB inputs are driven by the adjacent local interconnect, which in turn can be driven by the MegaLAB or FastTrack Interconnect. Because the ESB can be driven by the local interconnect, an adjacent LE can drive it directly for fast memory access. ESB outputs drive the MegaLAB and FastTrack Interconnect. In addition, ten ESB outputs, nine of which are unique output lines, drive the local interconnect for fast connection to adjacent LEs or for fast feedback product-term logic.

When implementing memory, each ESB can be configured in any of the following sizes: 128×16 , 256×8 , 512×4 , $1,024 \times 2$, or $2,048 \times 1$. By combining multiple ESBs, the Quartus II software implements larger memory blocks automatically. For example, two 128×16 RAM blocks can be combined to form a 128×32 RAM block, and two 512×4 RAM blocks can be combined to form a 512×8 RAM block. Memory performance does not degrade for memory blocks up to 2,048 words deep. Each ESB can implement a 2,048-word-deep memory; the ESBs are used in parallel, eliminating the need for any external control logic and its associated delays.

To create a high-speed memory block that is more than 2,048 words deep, ESBs drive tri-state lines. Each tri-state line connects all ESBs in a column of MegaLAB structures, and drives the MegaLAB interconnect and row and column FastTrack Interconnect throughout the column. Each ESB incorporates a programmable decoder to activate the tri-state driver appropriately. For instance, to implement 8,192-word-deep memory, four ESBs are used. Eleven address lines drive the ESB memory, and two more drive the tri-state decoder. Depending on which 2,048-word memory page is selected, the appropriate ESB driver is turned on, driving the output to the tri-state line. The Quartus II software automatically combines ESBs with tri-state lines to form deeper memory blocks. The internal tri-state control logic is designed to avoid internal contention and floating lines. See Figure 18.



Figure 18. Deep Memory Block Implemented with Multiple ESBs

The ESB implements two forms of dual-port memory: read/write clock mode and input/output clock mode. The ESB can also be used for bidirectional, dual-port memory applications in which two ports read or write simultaneously. To implement this type of dual-port memory, two or four ESBs are used to support two simultaneous reads or writes. This functionality is shown in Figure 19.



Advanced I/O Standard Support

APEX 20KE IOEs support the following I/O standards: LVTTL, LVCMOS, 1.8-V I/O, 2.5-V I/O, 3.3-V PCI, PCI-X, 3.3-V AGP, LVDS, LVPECL, GTL+, CTT, HSTL Class I, SSTL-3 Class I and II, and SSTL-2 Class I and II.



For more information on I/O standards supported by APEX 20KE devices, see *Application Note* 117 (*Using Selectable I/O Standards in Altera Devices*).

The APEX 20KE device contains eight I/O banks. In QFP packages, the banks are linked to form four I/O banks. The I/O banks directly support all standards except LVDS and LVPECL. All I/O banks can support LVDS and LVPECL with the addition of external resistors. In addition, one block within a bank contains circuitry to support high-speed True-LVDS and LVPECL inputs, and another block within a particular bank supports high-speed True-LVDS and LVPECL outputs. The LVDS blocks support all of the I/O standards. Each I/O bank has its own VCCIO pins. A single device can support 1.8-V, 2.5-V, and 3.3-V interfaces; each bank can support a different standard independently. Each bank can also use a separate V_{REF} level so that each bank can support any of the terminated standards (such as SSTL-3) independently. Within a bank, any one of the terminated standards can be supported. EP20K300E and larger APEX 20KE devices support the LVDS interface for data pins (smaller devices support LVDS clock pins, but not data pins). All EP20K300E and larger devices support the LVDS interface for data pins up to 155 Mbit per channel; EP20K400E devices and larger with an X-suffix on the ordering code add a serializer/deserializer circuit and PLL for higher-speed support.

Each bank can support multiple standards with the same VCCIO for output pins. Each bank can support one voltage-referenced I/O standard, but it can support multiple I/O standards with the same VCCIO voltage level. For example, when VCCIO is 3.3 V, a bank can support LVTTL, LVCMOS, 3.3-V PCI, and SSTL-3 for inputs and outputs.

When the LVDS banks are not used as LVDS I/O banks, they support all of the other I/O standards. Figure 29 shows the arrangement of the APEX 20KE I/O banks.

APEX 20KE devices also support the MultiVolt I/O interface feature. The APEX 20KE VCCINT pins must always be connected to a 1.8-V power supply. With a 1.8-V V_{CCINT} level, input pins are 1.8-V, 2.5-V, and 3.3-V tolerant. The VCCIO pins can be connected to either a 1.8-V, 2.5-V, or 3.3-V power supply, depending on the I/O standard requirements. When the VCCIO pins are connected to a 1.8-V power supply, the output levels are compatible with 1.8-V systems. When VCCIO pins are connected to a 2.5-V power supply, the output levels are compatible with 2.5-V systems. When VCCIO pins are connected to a 3.3-V power supply, the output levels are sometime with 2.5-V systems. When VCCIO pins are connected to a 3.3-V power supply, the output high is 3.3 V and compatible with 3.3-V or 5.0-V systems. An APEX 20KE device is 5.0-V tolerant with the addition of a resistor.

Table 13 summarizes APEX 20KE MultiVolt I/O support.

Table 13. APEX 20KE MultiVolt I/O Support Note (1)										
V _{CCIO} (V)		Input Siç	jnals (V)			Output S	ignals (V)			
	1.8	2.5	3.3	5.0	1.8	2.5	3.3	5.0		
1.8	>	\checkmark	>		\checkmark					
2.5	\checkmark	\checkmark	\checkmark			 Image: A start of the start of				
3.3	~	\checkmark	>	(2)			√ (3)			

Notes to Table 13:

 The PCI clamping diode must be disabled to drive an input with voltages higher than V_{CCIO}, except for the 5.0-V input case.

(2) An APEX 20KE device can be made 5.0-V tolerant with the addition of an external resistor. You also need a PCI clamp and series resistor.

(3) When V_{CCIO} = 3.3 V, an APEX 20KE device can drive a 2.5-V device with 3.3-V tolerant inputs.

ClockLock & ClockBoost Features

APEX 20K devices support the ClockLock and ClockBoost clock management features, which are implemented with PLLs. The ClockLock circuitry uses a synchronizing PLL that reduces the clock delay and skew within a device. This reduction minimizes clock-to-output and setup times while maintaining zero hold times. The ClockBoost circuitry, which provides a clock multiplier, allows the designer to enhance device area efficiency by sharing resources within the device. The ClockBoost circuitry allows the designer to distribute a low-speed clock and multiply that clock on-device. APEX 20K devices include a high-speed clock tree; unlike ASICs, the user does not have to design and optimize the clock tree. The ClockLock and ClockBoost features work in conjunction with the APEX 20K device's high-speed clock to provide significant improvements in system performance and band-width. Devices with an X-suffix on the ordering code include the ClockLock circuit.

The ClockLock and ClockBoost features in APEX 20K devices are enabled through the Quartus II software. External devices are not required to use these features.

The APEX 20K device instruction register length is 10 bits. The APEX 20K device USERCODE register length is 32 bits. Tables 20 and 21 show the boundary-scan register length and device IDCODE information for APEX 20K devices.

Table 20. APEX 20K Boundary-Scan Register Length							
Device	Boundary-Scan Register Length						
EP20K30E	420						
EP20K60E	624						
EP20K100	786						
EP20K100E	774						
EP20K160E	984						
EP20K200	1,176						
EP20K200E	1,164						
EP20K300E	1,266						
EP20K400	1,536						
EP20K400E	1,506						
EP20K600E	1,806						
EP20K1000E	2,190						
EP20K1500E	1 (1)						

Note to Table 20:

(1) This device does not support JTAG boundary scan testing.

Device		IDCODE (32 Bits) (1)								
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	1 (1 Bit) (2)						
EP20K30E	0000	1000 0000 0011 0000	000 0110 1110	1						
EP20K60E	0000	1000 0000 0110 0000	000 0110 1110	1						
EP20K100	0000	0000 0100 0001 0110	000 0110 1110	1						
EP20K100E	0000	1000 0001 0000 0000	000 0110 1110	1						
EP20K160E	0000	1000 0001 0110 0000	000 0110 1110	1						
EP20K200	0000	0000 1000 0011 0010	000 0110 1110	1						
EP20K200E	0000	1000 0010 0000 0000	000 0110 1110	1						
EP20K300E	0000	1000 0011 0000 0000	000 0110 1110	1						
EP20K400	0000	0001 0110 0110 0100	000 0110 1110	1						
EP20K400E	0000	1000 0100 0000 0000	000 0110 1110	1						
EP20K600E	0000	1000 0110 0000 0000	000 0110 1110	1						
EP20K1000E	0000	1001 0000 0000 0000	000 0110 1110	1						

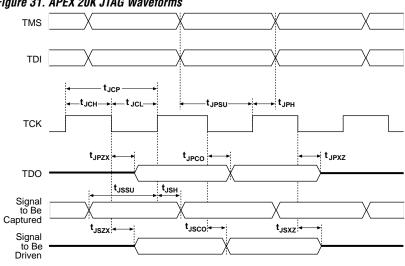
11- 04 00 04 4 ~

Notes to Table 21:

The most significant bit (MSB) is on the left. (1)

(2) The IDCODE's least significant bit (LSB) is always 1.

Figure 31 shows the timing requirements for the JTAG signals.





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Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
V _{OL}	3.3-V low-level TTL output voltage	I _{OL} = 12 mA DC, V _{CCIO} = 3.00 V (11)			0.45	V
	3.3-V low-level CMOS output voltage	I _{OL} = 0.1 mA DC, V _{CCIO} = 3.00 V (11)			0.2	V
	3.3-V low-level PCI output voltage	$I_{OL} = 1.5 \text{ mA DC},$ $V_{CCIO} = 3.00 \text{ to } 3.60 \text{ V}$ (11)			$0.1 imes V_{CCIO}$	V
	2.5-V low-level output voltage	I _{OL} = 0.1 mA DC, V _{CCIO} = 2.30 V (11)			0.2	V
	I _{OL} = 1 mA DC, V _{CCIO} = 2.30 V (11)			0.4	V	
	I _{OL} = 2 mA DC, V _{CCIO} = 2.30 V (11)			0.7	V	
l _l	Input pin leakage current	$V_1 = 5.75$ to -0.5 V	-10		10	μA
I _{OZ}	Tri-stated I/O pin leakage current	V _O = 5.75 to -0.5 V	-10		10	μΑ
I _{CC0}	V _{CC} supply current (standby) (All ESBs in power-down mode)	V_1 = ground, no load, no toggling inputs, -1 speed grade (12)		10		mA
	V _I = ground, no load, no toggling inputs, -2, -3 speed grades (12)		5		mA	
R _{CONF}	Value of I/O pin pull-up resistor	V _{CCIO} = 3.0 V (13)	20		50	W
	before and during configuration	V _{CCIO} = 2.375 V (13)	30		80	W

Symbol	Parameter	Conditions
t _{INSUBIDIR}	Setup time for bidirectional pins with global clock at LAB adjacent Input Register	
t _{INHBIDIR}	Hold time for bidirectional pins with global clock at LAB adjacent Input Register	
^t OUTCOBIDIR	Clock-to-output delay for bidirectional pins with global clock at IOE output register	C1 = 10 pF
t _{XZBIDIR}	Synchronous Output Enable Register to output buffer disable delay	C1 = 10 pF
t _{ZXBIDIR}	Synchronous Output Enable Register output buffer enable delay	C1 = 10 pF
^t INSUBIDIRPLL	Setup time for bidirectional pins with PLL clock at LAB adjacent Input Register	
t _{INHBIDIRPLL}	Hold time for bidirectional pins with PLL clock at LAB adjacent Input Register	
^t OUTCOBIDIRPLL	Clock-to-output delay for bidirectional pins with PLL clock at IOE output register	C1 = 10 pF
t _{XZBIDIRPLL}	Synchronous Output Enable Register to output buffer disable delay with PLL	C1 = 10 pF
t _{ZXBIDIRPLL}	Synchronous Output Enable Register output buffer enable delay with PLL	C1 = 10 pF

Note to Tables 38 and 39:

Г

(1) These timing parameters are sample-tested only.

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Units
	Min	Мах	Min	Max	Min	Max	
t _{SU}	0.5		0.6		0.8		ns
t _H	0.7		0.8		1.0		ns
t _{co}		0.3		0.4		0.5	ns
t _{lut}		0.8		1.0		1.3	ns
t _{ESBRC}		1.7		2.1		2.4	ns
t _{ESBWC}		5.7		6.9		8.1	ns
t _{ESBWESU}	3.3		3.9		4.6		ns
t _{ESBDATASU}	2.2		2.7		3.1		ns
t _{ESBDATAH}	0.6		0.8		0.9		ns
t _{ESBADDRSU}	2.4		2.9		3.3		ns
t _{ESBDATACO1}		1.3		1.6		1.8	ns
t _{ESBDATACO2}		2.6		3.1		3.6	ns
t _{ESBDD}		2.5		3.3		3.6	ns
t _{PD}		2.5		3.0		3.6	ns
t _{PTERMSU}	2.3		2.7		3.2		ns
t _{PTERMCO}		1.5		1.8		2.1	ns
t _{F1-4}		0.5		0.6		0.7	ns
t _{F5-20}		1.6		1.7		1.8	ns
t _{F20+}		2.2		2.2		2.3	ns
t _{CH}	2.0		2.5		3.0		ns
t _{CL}	2.0		2.5		3.0		ns
t _{CLRP}	0.3		0.4		0.4		ns
t _{PREP}	0.4		0.5		0.5		ns
t _{ESBCH}	2.0		2.5		3.0		ns
t _{ESBCL}	2.0		2.5		3.0		ns
t _{ESBWP}	1.6		1.9		2.2		ns
t _{ESBRP}	1.0		1.3		1.4		ns

Symbol	-1			-2		-3	
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		1.83		2.57		3.79	ns
t _{ESBSRC}		2.46		3.26		4.61	ns
t _{ESBAWC}		3.50		4.90		7.23	ns
t _{ESBSWC}		3.77		4.90		6.79	ns
t _{ESBWASU}	1.59		2.23		3.29		ns
t _{ESBWAH}	0.00		0.00		0.00		ns
t _{ESBWDSU}	1.75		2.46		3.62		ns
t _{ESBWDH}	0.00		0.00		0.00		ns
t _{ESBRASU}	1.76		2.47		3.64		ns
t _{ESBRAH}	0.00		0.00		0.00		ns
t _{ESBWESU}	1.68		2.49		3.87		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	0.08		0.43		1.04		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.29		0.72		1.46		ns
t _{ESBRADDRSU}	0.36		0.81		1.58		ns
t _{ESBDATACO1}		1.06		1.24		1.55	ns
t _{ESBDATACO2}		2.39		3.35		4.94	ns
t _{ESBDD}		3.50		4.90		7.23	ns
t _{PD}		1.72		2.41		3.56	ns
t _{PTERMSU}	0.99		1.56		2.55		ns
t _{PTERMCO}		1.07		1.26		1.08	ns

Symbol	-1		-	2	-	Unit	
-	Min	Max	Min	Max	Min	Max	
t _{insubidir}	2.77		2.91		3.11		ns
t _{inhbidir}	0.00		0.00		0.00		ns
toutcobidir	2.00	4.84	2.00	5.31	2.00	5.81	ns
t _{XZBIDIR}		6.47		7.44		8.65	ns
t _{ZXBIDIR}		6.47		7.44		8.65	ns
t _{insubidirpll}	3.44		3.24		-		ns
t _{inhbidirpll}	0.00		0.00		-		ns
toutcobidirpll	0.50	3.37	0.50	3.69	-	-	ns
t _{xzbidirpll}		5.00		5.82		-	ns
t _{zxbidirpll}		5.00		5.82		-	ns

Tables 61 through 66 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K100E APEX 20KE devices.

Table 61. EP20K100E f _{MAX} LE Timing Microparameters											
Symbol	-	1	-	2	-;	3	Unit				
	Min	Max	Min	Max	Min	Max					
t _{SU}	0.25		0.25		0.25		ns				
t _H	0.25		0.25		0.25		ns				
t _{CO}		0.28		0.28		0.34	ns				
t _{LUT}		0.80		0.95		1.13	ns				

Symbol	-1		-2			Unit	
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		1.79		2.44		3.25	ns
t _{ESBSRC}		2.40		3.12		4.01	ns
t _{ESBAWC}		3.41		4.65		6.20	ns
t _{ESBSWC}		3.68		4.68		5.93	ns
t _{ESBWASU}	1.55		2.12		2.83		ns
t _{ESBWAH}	0.00		0.00		0.00		ns
t _{ESBWDSU}	1.71		2.33		3.11		ns
t _{ESBWDH}	0.00		0.00		0.00		ns
t _{ESBRASU}	1.72		2.34		3.13		ns
t _{ESBRAH}	0.00		0.00		0.00		ns
t _{ESBWESU}	1.63		2.36		3.28		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	0.07		0.39		0.80		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.27		0.67		1.17		ns
t _{ESBRADDRSU}	0.34		0.75		1.28		ns
t _{ESBDATACO1}		1.03		1.20		1.40	ns
t _{ESBDATACO2}		2.33		3.18		4.24	ns
t _{ESBDD}		3.41		4.65		6.20	ns
t _{PD}		1.68		2.29		3.06	ns
t _{PTERMSU}	0.96		1.48		2.14		ns
t _{PTERMCO}		1.05		1.22		1.42	ns

Table 81. EP2	OK300E f _{MAX} I	Routing Delays	S				
Symbol	-	1		-2	-;	3	Unit
	Min	Max	Min	Max	Min	Мах	
t _{F1-4}		0.22		0.24		0.26	ns
t _{F5-20}		1.33		1.43		1.58	ns
t _{F20+}		3.63		3.93		4.35	ns

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Tables 85 through 90 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K400E APEX 20KE devices.

Table 85. EP20K400E f _{MAX} LE Timing Microparameters										
Symbol	-1 Spee	ed Grade	-2 Spe	ed Grade	-3 Spee	Unit				
	Min	Max	Min	Max	Min	Max				
t _{SU}	0.23		0.23		0.23		ns			
t _H	0.23		0.23		0.23		ns			
t _{CO}		0.25		0.29		0.32	ns			
t _{LUT}		0.70		0.83		1.01	ns			

Symbol	-1 Spee	d Grade	-2 Spee	ed Grade	-3 Spee	d Grade	Unit
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		1.67		1.91		1.99	ns
t _{ESBSRC}		2.30		2.66		2.93	ns
t _{ESBAWC}		3.09		3.58		3.99	ns
t _{ESBSWC}		3.01		3.65		4.05	ns
t _{ESBWASU}	0.54		0.63		0.65		ns
t _{ESBWAH}	0.36		0.43		0.42		ns
t _{ESBWDSU}	0.69		0.77		0.84		ns
t _{ESBWDH}	0.36		0.43		0.42		ns
t _{ESBRASU}	1.61		1.77		1.86		ns
t _{ESBRAH}	0.00		0.00		0.01		ns
t _{ESBWESU}	1.35		1.47		1.61		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	-0.18		-0.30		-0.27		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	-0.02		-0.11		-0.03		ns
t _{ESBRADDRSU}	0.06		-0.01		-0.05		ns
t _{ESBDATACO1}		1.16		1.40		1.54	ns
t _{ESBDATACO2}		2.18		2.55		2.85	ns
t _{ESBDD}		2.73		3.17		3.58	ns
t _{PD}		1.57		1.83		2.07	ns
t _{PTERMSU}	0.92		0.99		1.18		ns
t _{PTERMCO}		1.18		1.43		1.17	ns

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Spee	Unit	
	Min	Max	Min	Max	Min	Max	
t _{CH}	2.00		2.50		2.75		ns
t _{CL}	2.00		2.50		2.75		ns
t _{CLRP}	0.18		0.26		0.34		ns
t _{PREP}	0.18		0.26		0.34		ns
t _{ESBCH}	2.00		2.50		2.75		ns
t _{ESBCL}	2.00		2.50		2.75		ns
t _{ESBWP}	1.17		1.68		2.18		ns
t _{ESBRP}	0.95		1.35		1.76		ns

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed	Unit	
	Min	Max	Min	Max	Min	Max	
t _{INSU}	2.74		2.74		2.87		ns
t _{INH}	0.00		0.00		0.00		ns
toutco	2.00	5.51	2.00	6.06	2.00	6.61	ns
tINSUPLL	1.86		1.96		-		ns
t _{INHPLL}	0.00		0.00		-		ns
toutcopll	0.50	2.62	0.50	2.91	-	-	ns

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Spee	Unit	
	Min	Max	Min	Max	Min	Max	
t _{insubidir}	0.64		0.98		1.08		ns
t _{inhbidir}	0.00		0.00		0.00		ns
toutcobidir	2.00	5.51	2.00	6.06	2.00	6.61	ns
t _{xzbidir}		6.10		6.74		7.10	ns
t _{zxbidir}		6.10		6.74		7.10	ns
t _{insubidirpll}	2.26		2.68		-		ns
t _{inhbidirpll}	0.00		0.00		-		ns
toutcobidirpll	0.50	2.62	0.50	2.91	-	-	ns
t _{xzbidirpll}		3.21		3.59		-	ns
t _{ZXBIDIRPLL}		3.21		3.59		-	ns

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Table 99. EP2	OK1000E f _{MAX}	Routing Dela	ys				
Symbol	bol -1 Speed G		-2 Spe	eed Grade -3 Speed Grade			Unit
	Min	Max	Min	Max	Min	Max	
t _{F1-4}		0.27		0.27		0.27	ns
t _{F5-20}		1.45		1.63		1.75	ns
t _{F20+}		4.15		4.33		4.97	ns

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Spee	Unit	
	Min	Max	Min	Max	Min	Max	
t _{CH}	1.25		1.43		1.67		ns
t _{CL}	1.25		1.43		1.67		ns
t _{CLRP}	0.20		0.20		0.20		ns
t _{PREP}	0.20		0.20		0.20		ns
t _{ESBCH}	1.25		1.43		1.67		ns
t _{ESBCL}	1.25		1.43		1.67		ns
t _{ESBWP}	1.28		1.51		1.65		ns
t _{ESBRP}	1.11		1.29		1.41		ns

Table 101. EP20K1000E External Timing Parameters										
Symbol	-1 Spee	d Grade	-2 Spee	ed Grade	-3 Speed	Unit				
	Min	Max	Min	Max	Min	Max				
t _{INSU}	2.70		2.84		2.97		ns			
t _{INH}	0.00		0.00		0.00		ns			
t _{outco}	2.00	5.75	2.00	6.33	2.00	6.90	ns			
t _{INSUPLL}	1.64		2.09		-		ns			
t _{INHPLL}	0.00		0.00		-		ns			
t _{outcopll}	0.50	2.25	0.50	2.99	-	-	ns			

Table 108. EP20K1500E External Bidirectional Timing Parameters									
Symbol	-1 Speed Grade		-2 Spee	d Grade	-3 Spee	Unit			
	Min	Мах	Min	Max	Min	Max			
t _{insubidir}	3.47		3.68		3.99		ns		
t _{inhbidir}	0.00		0.00		0.00		ns		
t _{outcobidir}	2.00	6.18	2.00	6.81	2.00	7.36	ns		
t _{XZBIDIR}		6.91		7.62		8.38	ns		
t _{zxbidir}		6.91		7.62		8.38	ns		
t _{insubidirpll}	3.05		3.26				ns		
t _{inhbidirpll}	0.00		0.00				ns		
t _{outcobidirpll}	0.50	2.67	0.50	2.99			ns		
t _{xzbidirpll}		3.41		3.80			ns		
t _{ZXBIDIRPLL}		3.41		3.80			ns		

Tables 109 and 110 show selectable I/O standard input and output delays for APEX 20KE devices. If you select an I/O standard input or output delay other than LVCMOS, add or subtract the selected speed grade to or from the LVCMOS value.

Table 109. Selectab	le I/O Standa	ard Input Dela	ays				
Symbol	-1 Spee	ed Grade	-2 Spe	-2 Speed Grade		-3 Speed Grade	
	Min	Max	Min	Max	Min	Max	Min
LVCMOS		0.00		0.00		0.00	ns
LVTTL		0.00		0.00		0.00	ns
2.5 V		0.00		0.04		0.05	ns
1.8 V		-0.11		0.03		0.04	ns
PCI		0.01		0.09		0.10	ns
GTL+		-0.24		-0.23		-0.19	ns
SSTL-3 Class I		-0.32		-0.21		-0.47	ns
SSTL-3 Class II		-0.08		0.03		-0.23	ns
SSTL-2 Class I		-0.17		-0.06		-0.32	ns
SSTL-2 Class II		-0.16		-0.05		-0.31	ns
LVDS		-0.12		-0.12		-0.12	ns
CTT		0.00		0.00		0.00	ns
AGP		0.00		0.00		0.00	ns

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